## CHANGE NOTIFICATION



December 05, 2013

Dear Sir/Madam: PCN# 120513

## Subject: Notification of Assembly Process Change for LTM8061

Please be advised that Linear Technology Corporation has made a minor change to the internal package construction to facilitate the use of one attach material for both die and components. The die attach material is changed from epoxy to solder, which is already used for attaching components in the same µModule device package. In order to use the solder die attach, the die attach paddle (DAP) has been modified by splitting the DAP into multiple pads for dice D1, D3 and U1. Linear has been shipping several µModule devices using solder for die attach and component attach.

Besides these changes, no functional, parametric, mechanical, or datasheet specifications are affected and the component bill of materials remains unchanged. Similarly, there are no changes associated with the package footprint, PCB layout or product top marking, so the customer applications will be unaffected.

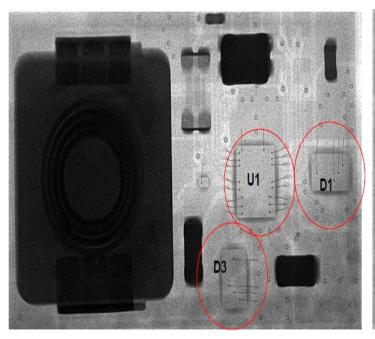
Parts incorporating the new substrate design have been fully characterized and tested for package level reliability. The change was qualified by performing extensive characterization over the full operating voltage and temperature ranges and MSL3 preconditioning. Devices from the same µModule device product families have been subjected to 1000 cycles of temperature cycles and thermal shock. Products built using the improved design are targeted for shipment after February 7, 2014.

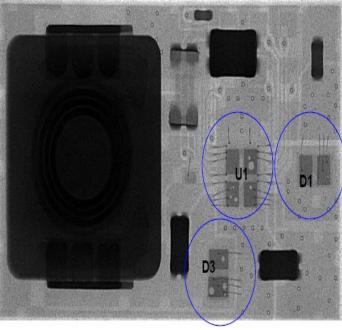
Should you have any further questions, please feel free to contact me at 408-432-1900 ext. 2077, or by E-mail <a href="mailto:JASON.HU@LINEAR.COM">JASON.HU@LINEAR.COM</a>. If I do not hear from you by February 6, 2014, we will consider this change approved by your company.

Sincerely,

Jason Hu Quality Assurance Engineer

LTM8061- Current and New Design





**Current Design** 

**New Design** 



## PACKAGE RELIABILITY DATA LTM80xx Solder Die Attach Qualification Report 11/8/2013 OPERATING LIFE TEST NUMBER K DEVICE DEVICE TYPE SAMPLE OLDEST DATE CODE NEWEST DATE CODE HOURS AT +150°C OF FAILURES LTM8008 1210 77.00 1210 0 77 77.00 0 J-STD-020 MSL 3 PRECONDITIONING: 192h +30°C/60%R.H. SOAK, 3x REFLOW AT +245°C PEAK NUMBER OLDEST DATE CODE NEWEST DATE CODE DEVICE SAMPLE SIZE FAILURES LTM8001 199 1236 1236 0 LTM8008 462 1210 1210 0 LTM8021 204 1306 1306 0 LTM8023 0 204 1245 1245 LTM8025 204 1245 1245 0 LTM8027 77 1320 1320 0 LTM8028 184 1236 1236 0 LTM8029 246 1239 1239 0 LTM8032 0 204 1302 1302 LTM8033 204 1306 1306 0 LTM8045 152 1225 1225 0 LTM8047 77 1242 1242 0 LTM8048 274 1232 1236 0 0 LTM8052 358 1239 1239 LTM8058 204 1239 1239 0 LTM8061 204 1309 1309 O LTM8062 231 1330 1330 0 3,688 0 HIGH TEMPERATURE BAKE at 150°C K DEVICE HOURS AT +150°C NUMBER DEVICE OLDEST DATE CODE NEWEST DATE CODE FAILURES LTM8001 25 1236 1236 25.00 0 LTM8008 77 77.00 0 1210 1210 LTM8021 50.00 O 50 1306 1306 LTM8023 50 1245 1245 50.00 0 LTM8025 50 1245 1245 50.00 0 LTM8029 1239 50.00 0 50 1239 LTM8032 74 1302 1302 74.00 0 LTM8033 77 1306 1306 77 00 n LTM8045 50 1225 1225 50.00 0 LTM8052 50 1239 1239 50.00 0 LTM8058 50 1239 1239 50.00 0 603 603.00 0 HIGHLY ACCELERATED STRESS TEST (+131°C/85%R.H. w BIAS) NUMBER K DEVICE DEVICE TYPE SAMPLE OLDEST NEWEST HOURS SIZE DATE CODE DATE CODE AT +85°C FAILURES LTM8008 1210 1210 46 88 32 O 46 88.32 0 UNBIASED HIGHLY ACCELERATED STRESS TEST (+131°C/85%R.H.) NUMBER K DEVICE DEVICE TYPE OLDEST DATE CODE NEWEST DATE CODE HOURS AT +131°C SIZE FAILURES LTM8001 43 1236 1236 4.13 0 LTM8023 50 1245 1245 4.80 0 LTM8025 50 1245 1245 4.80 O LTM8028 30 1236 1236 2.88 0 LTM8029 70 1239 1239 6.72 0 LTM8032 50 1302 1302 4.80 0 0 LTM8033 50 1306 1306 4.80 LTM8045 49 1225 1225 8.23 0 4.80 LTM8052 50 1239 1239 O LTM8058 50 1239 1239 4.80 0 LTM8061 50 1309 1309 4.80 0

57.77

0

588



## PACKAGE RELIABILITY DATA LTM80xx Solder Die Attach Qualification Report 11/8/2013

LTM80xx Solder Die Attach Qualification Report					
11/8/2013					
• TEMPERATURE/HUMIDITY STORAGE (+85°C/85%R.H.) (1)					
				K DEVICE	NUMBER
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	HOURS AT +85°C	OF FAILURES
LTM8008	77 77	1210	1210	77.00 77.00	0
• TEMP CYCLE FROM -65°C to +150°C (1)					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
LTM8008	231	1210	1210	231.00	0
LTM8032	77	1302	1302	77.00	0
LTM8033	77	1306	1306	77.00	0
LTM8052 LTM8061	77 77	1239 1309	1239 1309	77.00 77.00	0
• TEMP CYCLE FR	539 OM -55°C to +125°	C <sup>(1)</sup>		539.00	0
DEVICE	SAMPLE	OLDEST	NEWEST	KDEVICE	NUMBER
TYPE	SIZE	DATE CODE	DATE CODE	CYCLES	OF FAILURES
LTM8001	77	1236	1236	77.00	0
LTM8021	77	1306	1306	77.00	0
LTM8023 LTM8025	77 77	1245 1245	1245 1245	77.00 77.00	0
LTM8027	77	1320	1320	77.00	0
LTM8028	77	1236	1236	77.00	Ō
LTM8029	77	1239	1239	77.00	0
LTM8045	77	1225	1225	77.00	0
LTM8047	77 102	1242 1232	1242 1236	77.00	0
LTM8048 LTM8052	102 77	1232	1236	140.50 77.00	0
LTM8058	77	1239	1239	77.00	0
	949		.200	987.50	Ö
• THERMAL SHOCK FROM -65°C to +150°C (1)					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
LTM8008	231	1210	1210	231.00	0
LTM8032	77	1302	1302	77.00	0
LTM8033	77	1306	1306	77.00	0
LTM8052	77	1239	1239	77.00	0
LTM8061	77 539	1309	1309	77.00	0
539 539.00 0 • THERMAL SHOCK FROM -55°C to +125°C (1)					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
1.TM0004	77	4220	4220	77.00	
LTM8001 LTM8021	77 77	1236 1306	1236 1306	77.00 77.00	0
LTM8023	77	1245	1245	77.00	0
LTM8025	77	1245	1245	77.00	Ö
LTM8028	77	1236	1236	77.00	0
LTM8029	77	1239	1239	77.00	0
LTM8045	75 426	1225	1225	75.00	0
LTM8048 LTM8052	126 77	1232 1239	1236 1239	126.00 77.00	0
LTM8058	77	1239	1239	77.00	0
817 817.00 0  • BOARD MOUNT TEMP CYCLE FROM -40°C to +125°C					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
LTM8008	15 15	1210	1210	22.50 22.50	0
(1) Environmental		by JEDEC Level 3 F	Preconditioning: 192	h 30°C/60% R.H. soa	
D. 6 + 04500					

Reflow at 245°C